Chinastandards.org

NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 4058-1995

Test method for detection of oxidation induced defects in polished silicon wafers

硅抛光片氧化诱生缺陷的检验方法

(English Translation)

Issued on: April 18, 1995 **Implemented on: December 1, 1995**

Issued by: State Bureau of Technical Supervision

Preview: page 1 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/gb-t-4058-1995

Chinastandards.org

Table of Contents

Document data

1 Document data

Sector: National standard (Recommended).

Issuing body: State Bureau of Technical Supervision.

Date of issue: 1995-04-18.

Date of implementation: 1995-12-01.

Status: obsolete, replaced by GB/T 4058-2009.

Preview: page 2 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/gb-t-4058-1995